

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/016,853 LIN ET AL.	
		Examiner	Art Unit	Page 1 of 1 David Q Nguyen 2681

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,101,382	08-2000	Granberg, Christer	455/414.1
	B	US-2002/0197991	12-2002	Anvekar et al.	455/432
	C	US-6,157,832	12-2000	Lahtinen, Lauri	455/433
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP410013945A	01-1998	JP	Tomoike, Hiromoto	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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